

Notice of References Cited

Application/Control No.

09/627,559

Applicant(s)/Patent Under

Reexamination

SCHULTZ ET AL.

Examiner

Bernard E Souw

Art Unit

2881

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6310679 B1	10/2001	Shiraishi;	
J	B	US-6233039 B1	5/2001	Yen et al.	
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"The Optics of Spectroscopy", Section 3: "Spectrometer Throughput and Etendue", downloaded from the Internet Website: wysiwyg://18/http://www.jyhoriba.co.uk/jy/oos/oos_ch3.htm
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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